

Notice of References Cited	Application/Control No. 10/779,779	Applicant(s)/Patent Under Reexamination NIIYA, HIROTAKA	
	Examiner Wen-Ying P. Chen	Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,697,138	02-2004	Ha et al.	349/114
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000162625 A	06-2000	Japan	NORITAKE et al.	G02F 01/1343
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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